Abstracts

16-Term Error Model and Calibration Procedure for on Wafer Network Analysis Measurements (1991 Vol. III [MWSYM])

J.V. Butler, D. Rytting, M.F. Iskander, R. Pollard and M.V. Bossche. "16-Term Error Model and Calibration Procedure for on Wafer Network Analysis Measurements (1991 Vol. III [MWSYM])." 1991 MTT-S International Microwave Symposium Digest 91.3 (1991 Vol. III [MWSYM]): 1125-1127.

Vector network measurements are enhanced by calibrating the measurement system at the device under test interface. Many measurement systems such as MMIC wafer probes contain leakage and coupling error terms not modeled in current calibration systems. In this paper, all possible error terms are included in a new 16-term error model and calibration procedure. Corrected measurements using the new 16-term calibration procedure are compared with TRL calibration measurements and excellent agreement was observed.

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